

**Notice of References Cited**

Application/Control No.

10/591,534

Applicant(s)/Patent Under  
Reexamination  
HAUKE ET AL.

Examiner

Dwan A. Gerido, Ph.D.

Art Unit

4151

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,302,480	11-1981	Fischer et al.	435/40.5
*	B	US-3,498,860	03-1970	PICKETT JOHN E P	156/57
*	C	US-4,011,350	03-1977	Markovits et al.	427/2.13
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.